

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)		Attorney Docket No.: 8051-1036		Application No. 10/156355 NEW NATIONAL PHASE		
		Applicant: Shinichi SUMIDA et al.				
		Filing Date: January 5, 2006		Group Art Unit:		
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	
Examiner Initial	Document Number	Date	Country	Class	Subclass	
Examiner Initial	Document Number	Date	Country	Class	Subclass	
FOREIGN PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation
	JP 2002-145962	5/22/2002	JAPAN			Yes
	JP 2002-206012	7/26/2002	JAPAN			No
	JP 2002-275215	9/25/2002	JAPAN			
	JP 2002-327013	11/15/2002	JAPAN			
	JP 2002-350179	12/4/2002	JAPAN			
	JP 2002-338633	11/27/2002	JAPAN			
	WO 01/98834	12/27/2001	INTERNATIONAL			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER:		DATE CONSIDERED				
<i>R. Denby</i>		<i>2-8-2007</i>				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						

* English language abstract provided for the Examiner's convenience

BC/gw

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U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Bp KODAMA et al., "Synthesis of Novel Fluoropolymer for 157 nm Photoresists by Cyclopolymerization", Proceedings of SPIE, Vol. 4690, 2002, pp. 76-83.

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